

<b>Notice of References Cited</b>	Application/Control No. 10/699,780		Applicant(s)/Patent Under Reexamination FENG ET AL.	
	Examiner JYOTHSNA A. VENKAT Ph. D		Art Unit 1615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,010,541	01-2000	de la Mettrie et al.	8/412
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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